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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

KARSTEN WIECZOREK
ROLF GEILENKEUSER
JÖRG-OLIVER WEIDNER

Examiner: Andre C. Stevenson

Group Art Unit: 2812

Serial No.: 10/649,051

Att'y Docket: 2000.108400/DE0349

Filed: August 27, 2003

Customer No.: 23720

For: INTEGRATED SEMICONDUCTOR
STRUCTURE FOR RELIABILITY
TESTS OF DIELECTRICS

RESPONSE TO FINAL OFFICE ACTION DATED JULY 13, 2005

Mail Stop AF
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

CERTIFICATE OF MAILING
37 C.F.R. 1.8

I hereby certify that this correspondence is being deposited with the U.S. Postal Service with sufficient postage as First Class Mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on the date below:

September 7, 2005
Date

May Paul
Signature

Sir:

This paper is submitted in response to the Final Office Action dated July 13, 2005, for which the three-month date for response is October 13, 2005.

No fees are believed to be due in connection with the present paper. **However, should any fees be required under 37 C.F.R. §§ 1.16 to 1.21, the Director is authorized to deduct such fees from Advanced Micro Devices, Inc. Deposit Account No. 01-0365/DE0349. In the event the monies in that account are insufficient, the Director is authorized to withdraw funds from Williams, Morgan & Amerson, P.C. Deposit Account No. 50-0786/2000.108400.**

Reconsideration of the application in view of the following amendments and remarks is respectfully requested.